

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applic. No. : PCT/DE2003/002580  
Applicant : Meier, Bernd et al.  
Int'l Filing Date: 31 July 2003  
Art Unit : N/A  
Examiner : N/A  
  
Docket No. : S4-02P11627  
Customer No.: 24131

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

In accordance with 37 C.F.R. 1.98 copies of the following patents and/or publications are submitted herewith:

U.S. Patent No. 5,142,286 (Ribner et al.), dated August 25, 1992;

U.S. Patent No. 5,329,281 (Baumgartner et al.), dated July 12, 1994;

European Patent Specification EP 0 577 902 B1 (Abbate et al.), dated January 12, 1994;

European Patent Application EP 0 804 038 A2 (Mizuno), dated October 29, 1997;

European Patent Application EP 0 367 522 A2 (Baumgartner), dated May 9, 1990;

German Patent DE 30 01 499 C2 (Ley et al.), dated August 28, 1980 and English

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /DHM/

abstract thereof;

German Patent DE 100 52 152 C1 (Herzer et al.), dated September 6, 2001 and English abstract thereof;

German Patent DE 35 09 762 C2 (Gerrath), dated September 25, 1986 and English abstract thereof;

German Published Non-Prosecuted Patent Application DE 100 42 587 A1 (Feldtkeller), dated March 14, 2002 and English abstract thereof;

German Published Non-Prosecuted Patent Application DE 40 20 219 A1 (Wolff et al.), dated August 14, 1991 and English abstract thereof;

German Patent DE 25 41 121 C3 (Oelsch), dated March 31, 1977, Measuring Arrangement for Signal Averaging;

German Patent DE 30 45 033 C2 (Beck), dated July 8, 1982, Arrangement for Fast Continuous Determining of Time Average of Analog Measured Value;

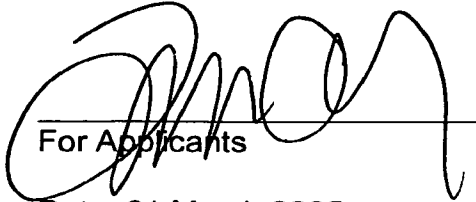
Japanese Patent and English Abstract JP 4-144423 (Kazuo et al.), dated May 18, 1992;

McCarthy, E. P.: "A True Averaging Circuit for Instrumentation", Electronic Engineering, May 1984, pp. 35 and 36.

If no translation of pertinent portions of any foreign language patents or publications mentioned above is included with the aforementioned copies of those applications, patents and/or publications, it is because no existing translation is readily available to the applicant.

As per the Notice in 1273 OG 55 (August 5, 2003) no copies of any above-mentioned U.S. patents and U.S. patent application publications are submitted for any application filed after June 30, 2003.

Respectfully submitted,



For Applicants

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Date: 21 March 2005

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/kf/cp

<b>FORM PTO-1449 (SUBSTITUTE)</b>  U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE  <b>INFORMATION DISCLOSURE          STATEMENT BY APPLICANT</b> (37 CFR 1.98(b))				Attorney Docket No.: S4-02P11627 Appl. No. PCT/DE2003/002580  Applicant MEIER, BERND ET AL.  Filing Date 21 March 2005 Group Art Unit			
EXAMINER INITIALS		PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
	A	5,142,286	8/25/92	Ribner et al.			
	B	5,329,281	7/12/94	Baumgartner et al.			
	C						
	D						
	E						
	F						
	G						
	H						
	I						
<b>FOREIGN PATENT DOCUMENT</b>							
		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES   NO
	J	0 577 902 B1	1/12/94	Europe			
	K	0 804 038 A2	10/29/97	Europe			
	L	0 367 522 A2	5/9/90	Europe			
	M	30 01 499 C2	8/28/80	Germany			
	N	100 52 152 C1	9/6/01	Germany			
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
<b>EXAMINER</b>				<b>DATE CONSIDERED</b>			
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EXAMINER INITIALS		PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
	A						
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<b>FOREIGN PATENT DOCUMENT</b>							
		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES   NO
	J	4-144423	5/18/92	Japan			
	K						
	L						
	M						
	N						
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
		McCarthy, E. P.: "A True Averaging Circuit for Instrumentation", Electronic Engineering, May 1984, pp. 35 and 36					
<b>EXAMINER</b> /David Maizahn/				<b>DATE CONSIDERED</b> 04/22/2008			
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							